

Notice of References Cited	Application/Control No. 10/530,358	Applicant(s)/Patent Under Reexamination SUNAGAWA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0022695	02-2002	Ueno et al.	525/165
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*	N	CN 1123302 A	05-1996	China	DING et al.	
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NON-PATENT DOCUMENTS

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